
Bringing up the BlueNRG-LP, BlueNRG-LPS devices

Introduction

The BlueNRG-LP, BlueNRG-LPS are high performance, ultra-low power wireless systems-on-chip, which support the Bluetooth® Low Energy specifications.

In order to achieve the maximum performance, some procedures must be carried out before finalizing the application.

This document summarizes the following fundamental steps:

- Application PCB test points
- Power supply and current consumption tests
- Device configuration
- XTAL and LSOSC centering tests
- Output power test
- Packet exchange test
- Sensitivity test
- Power consumption in advertising mode.

Note: The document content is valid both for the BlueNRG-LP and BlueNRG-LPS devices. Any reference to the BlueNRG-LP device and platform is also valid for the BlueNRG-LPS device and platform. Any specific difference is highlighted whenever it is needed.

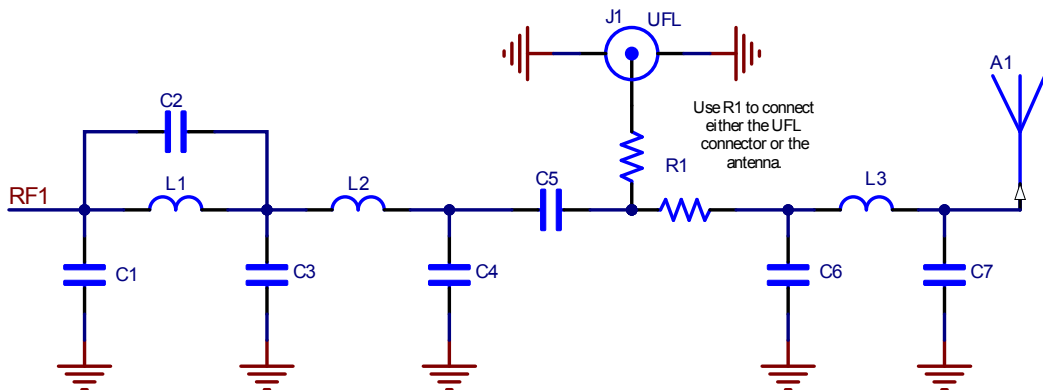
1 Application PCB test points

ST recommends a set of test points to measure the performance of the device on the customer's PCB. According to PCB constraints, it may not always be possible to add all test points, therefore some tests cannot be performed.

Table 1. Test points

Test point	Function	Details of the test point
Current consumption	Should be added to the PCB to measure the BlueNRG-LP, BlueNRG-LPS current consumption	In series with the VDD1,2,3,4, VDDRF, and VDDSD pins
Voltage supply	Should be added to measure the BlueNRG-LP, BlueNRG-LPS supply voltages	To pins: VCAP, VDDA, VLXSD, VFBSD
RF	If the PCB uses an embedded antenna, like a PCB or a chip antenna, it is recommended to add a UFL connector to allow measurement of the RF performance with a spectrum analyzer	Between the matching network and the embedded antenna (refer to Figure 1. UFL connector)

Figure 1. UFL connector



1.1 DTM test applications

DTM (direct test mode) test application is used as reference software to configure the platform under test. DTM binary file can be built using the DTM test application available on the BlueNRG-LP, BlueNRG-LPS software package (STSW-BNRGLP-DK) in the BLE_Examples/DTM folder, and it can be directly loaded on related STEVAL board using the mass storage capability or the RF-Flasher utility. Based on the test requirements, the user can select:

- DTM UART image
- DTM SPI image.

The pre-built binary images for the BlueNRG-LP STEVAL-IDB011V1/V2 (DTM UART/SPI mode) are available in the BlueNRG-LP DK software package in folders: Firmware/BLE_Examples/DTM/STEVAL-IDB011V1.

The pre-built binary images for the BlueNRG-LPS STEVAL-IDB012V1 (DTM UART/SPI mode) are available in the BlueNRG-LP DK software package in folders: Firmware/BLE_Examples/DTM/STEVAL-IDB012V1.

2 Power supply test

2.1 Test case specification identifier

SUPPLY_TEST

No specific firmware is needed for this test.

2.2 Test prerequisite

In order to perform this test, it is necessary to add some test points to the platform. Refer to [Section 1 Application PCB test points](#) for test pin description.

2.3 Test description

The aim of this test is to ensure that the BlueNRG-LP/BlueNRG-LPS are correctly powered.

2.4 Test setup

2.4.1 Hardware

A multimeter is required for this test.

2.4.2 Software

DTM binary file loaded into the BlueNRG-LP/BlueNRG-LPS devices. Please refer to [Section 1.1 DTM test applications](#).

2.5 Test procedure

Power up the BlueNRG-LP/BlueNRG-LPS platforms.

Measure the voltage in: VDD1,2,3,4, VDDRF, VDDSD, VCAP, VDDA, VLXSD and VFBS.

2.6 Expected results

The measured pin voltage and current should be aligned with the following values if the DC-DC converter ON configuration has been chosen.

Table 2. Supply test results

Pin	Expected value
VDD1,2,3,4, VDDRF and VDDSD	1.7 – 3.6 V
VCAP and VDDA	1.2 V
VLXSD	Square wave around 1.2 – 1.95 V
VFBS	1.2 – 1.95 V

If the DC-DC converter OFF configuration has been chosen, the VLXSD pin is left floating and the VFBS pin is connected directly to VBAT.

2.7 Note

If some of the measured values are not aligned with the expected values, it is recommended to double-check the integrity of the board connection.

2.8 Other

N/A.

3 Device configuration

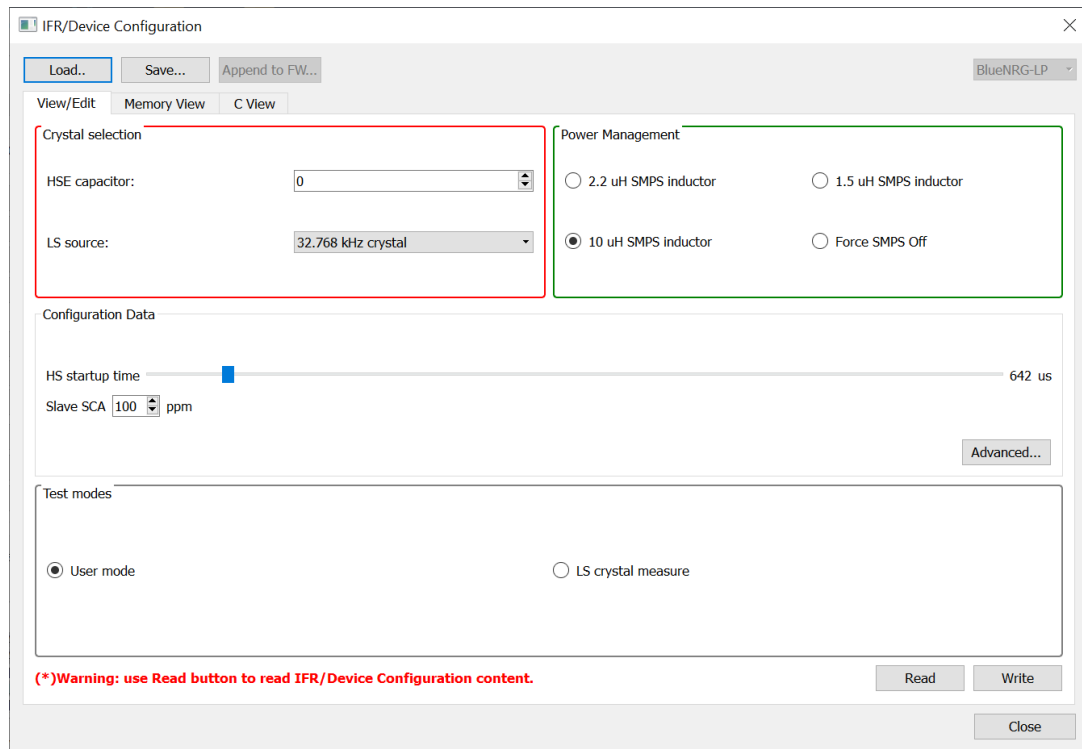
There are some parameters of the BlueNRG-LP/BlueNRG-LPS devices that must be defined and used during software initialization, before the application board is finalized.

These parameters are:

- Low speed oscillator source (32 kHz or the internal ring oscillator)
- Power management options (SMPS inductor or SMPS off configuration)
- Change HS start-up time parameter from 512 μ s to 1953 μ s
- Sleep clock accuracy.

When the DTM firmware is used, the device configuration parameters can be set using the BlueNRG GUI PC application available on the BlueNRG GUI SW package (STSW-BNRGUI).

Figure 2. BlueNRG GUI device configuration tool



4 HS_Startup_Time

The high speed external clock oscillator (HSE) needs time in order to be ready after system wake-up, upon exit from Deepstop mode. A parameter, referred to as HS_STARTUP_TIME inside the firmware examples, reflects this time. It needs to be tuned in order to let the radio transmit and receive at the programmed instants if the system exits from Deepstop. Higher values are safer, but they may lead to unnecessary extra power consumption since the system wakes up too early in order to give time to the HSE to be ready before transmission or reception. A too short value instead prevents the BlueNRG-LP/BlueNRG-LPS from correctly sending or receiving packets.

4.1 Test case specification identifier

HS_XTAL_startup_TEST.

4.2 Test prerequisite

- A power source at the lowest operating voltage
- One of the following:
 - access to the UART interface OR
 - an oscilloscope and access to VCAP pin and one GPIO (default PB6).

4.3 Test description

The aim of this test is to measure the HSE start-up time in the worst condition. A firmware application measures the HSE start-up time using the internal clock as a reference (assuming the frequency of the HSE is correct, since it is needed to calibrate the internal clock for measurement).

A pulse is also generated on a configurable GPIO (PB6 is the default) when HSE is ready. This is useful in case there is no access to the UART interface or just to double check.

4.4 Test setup

4.4.1 Hardware

A serial terminal connected to the board to receive data from UART. As an alternative, an oscilloscope is required for this test.

4.4.2 Software

RCC_HSEStartupTest firmware application on the STSW-BNRGLP-DK, BlueNRG-LP/BlueNRG-LPS SDK, Projects\Peripheral_Examples\MIX\RCC. This application programs periodic wake-up of the system and it measures the start-up time of the HSE at each wake-up. The current and longer (worst) measure is reported on the UART interface.

4.5 Test procedure

- Load firmware into BlueNRG-LP/BlueNRG-LPS
- Power the device at the lowest supported operating voltage: this is the condition in which the HSE needs more time to be ready
- Run the test at ambient temperature (around 25 °C).

4.6 Expected results

The application outputs on the UART interface information about the measured start-up time.

Increasing the longer reported value by 10% in order to consider variation from 25 °C to 105 °C. Increasing again the value by 30% to have a safe margin, since variation of the crystal parameters like motional inductance and capacitance influence the start-up time.

$HS_STARTUP_TIME = measured_value * 1.1 * 1.3.$

4.7 **Note**

The measurement should be taken on a sufficient number of boards in order to have the knowledge of the distribution of this value in the entire set of boards.

4.8 **Other**

As an alternative, the start-up time can be obtained by measuring time from when the voltage begins to rise on VCAP pin and the time the voltage on the test GPIO is high. The test GPIO can be easily changed (default is PB6).

5 HSOSC centering test

The BlueNRG-LP/BlueNRG-LPS integrate a low-speed frequency oscillator (LSOSC) and a high-speed (32 MHz) frequency oscillator (HSOSC).

The low frequency clock is used in low power mode and can be supplied either by a 32.7 kHz oscillator that uses an external crystal or by an internal ring oscillator, which does not require any external components.

The primary high frequency clock is a 32 MHz crystal oscillator.

The frequency tolerance of the high-speed crystal oscillator must be below ± 50 ppm.

The BlueNRG-LP/BlueNRG-LPS devices, as with all RF systems, are highly dependent on accurate clocks for the correct operation. A deviation in clock frequency directly deviates the radio frequency, and this can degrade RF performance, violate legal requirements or in the worst case lead to a non-functioning system.

For these reasons, the crystal frequency must be centered and this has to be done by choosing the optimum load capacitors for a given circuit and layout. The easiest way to find the correct load capacitance is through the experimentation. The BlueNRG-LP/BlueNRG-LPS make the process of finding the correct capacitor value very easy. In fact, it has an integrated capacitor bank that can be set by software. In this way, no external capacitors are needed, for maximum flexibility, and the cost of external components as well as space on the board are saved.

5.1 Test case specification identifier

HSOSC_center_TEST.

5.2 Test prerequisite

For this test, the UFL connector (see [Table 1. Test points](#)) is not mandatory.

5.3 Test description

For the reasons previously explained, the crystal frequency must be centered, and the optimum load capacitor values can be found through experimentation. The radio can be set by fixing a constant carrier at a given frequency.

By measuring the output frequency with a spectrum analyzer, the offset can be easily found.

5.4 Test setup

5.4.1 Hardware

A spectrum analyzer is required for this test.

5.4.2 Software

The ST BlueNRG GUI and DTM binary file loaded in the BlueNRG-LP/BlueNRG-LPS device. Refer to [Section 1.1 DTM test applications](#).

5.5 Test procedure

The following procedure is valid for the high-speed oscillator (32 MHz):

Connect the BlueNRG-LP/BlueNRG-LPS board to the spectrum analyzer through an RF cable if it is equipped with UFL connector, otherwise plug a 2.4 GHz antenna into the input port of the instrument.

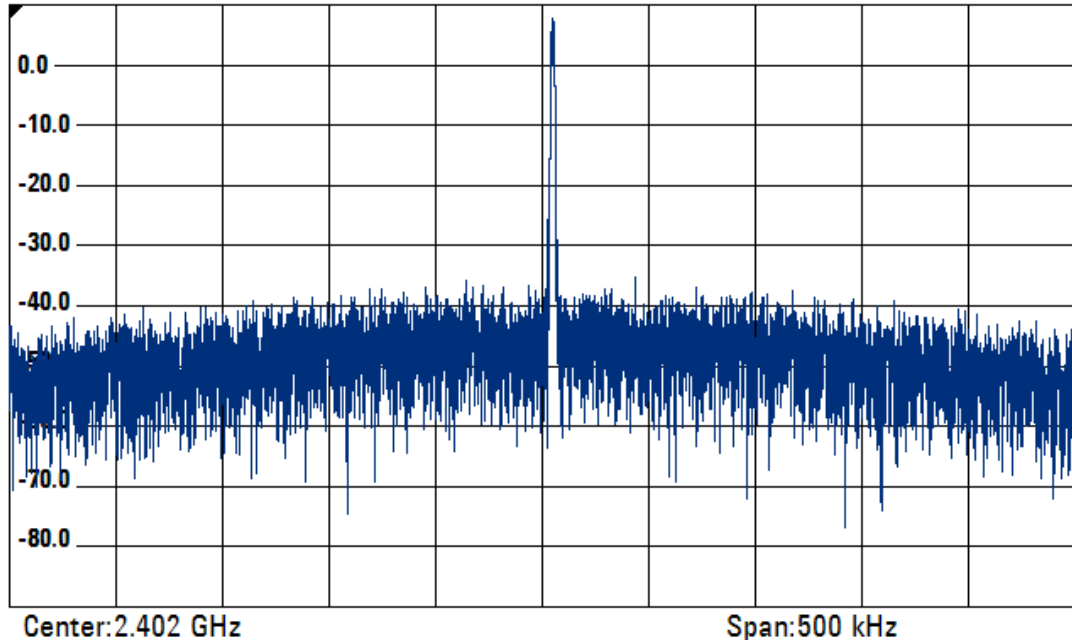
Power up the selected platform.

Set the spectrum analyzer to: res BW = 1 kHz, SPAN = 500 kHz (see [Figure 3. Frequency tone at Ch0 for the XTAL center test](#)).

Generate a carrier wave tone at Ch0 (freq. 2.402 GHz) using the BlueNRG GUI, RF test window, start tone button and selecting TX frequency as 2402 MHz, channel 0 (a tone can be emitted at $f = 2402 + k \cdot 2$ MHz, with $k = 0$ to 39).

The difference between the desired tone and the measured tone is the frequency offset.

Figure 3. Frequency tone at Ch0 for the XTAL center test



5.6 Expected results

The offset limit is:

$$|\text{Offset}| < 50 \text{ kHz}$$

If DUT frequency > 2402.05 MHz → increases XTAL caps

If DUT frequency < 2401.95 MHz → decreases XTAL caps

5.7 Note

Load capacitor value can be increased by choosing a higher value of SWXOTUNE in the RCC_RFSWHSECR register.

Use CONFIG_HW_HSE_TUNE to set the correct value (e.g. CONFIG_HW_HSE_TUNE=32). In DTM application, the user can change the value through a Device configuration parameter (or force the firmware to use a given value by defining the macro CONFIG_HW_HSE_TUNE).

5.8 Other

N/A.

6 LSOSC centering test

The LSOSC is used to have a reference time clock. The advantage of using the external 32.768 kHz clock is that it consumes less power than internal RO and it is more accurate (typ. 50 ppm). This test allows its oscillator frequency to be centered, changing the crystal capacitance.

6.1 Test case specification identifier

LSOSC_center_TEST.

6.2 Test prerequisite

For this test, access to PA10 pin is required. Pin can be changed to PA4 if needed.

6.3 Test description

There is a way, using the device configuration tool of the BlueNRG GUI, to put the LSOSC signal to PA10. By measuring its frequency with an oscilloscope, the frequency offset can easily be measured.

6.4 Test setup

6.4.1 Hardware

An oscilloscope is required for this test.

6.4.2 Software

The ST BlueNRG GUI and DTM binary file loaded in the BlueNRG-LP/BlueNRG-LPS devices. Refer to [Section 1.1 DTM test applications](#).

6.5 Test procedure

Connect an oscilloscope probe to PA10. Power up the BlueNRG-LP/BlueNRG-LPS platform.

Set the scope to capture a consistent number of 32 kHz waveform periods (for example 64 cycles, so set the time base at 200 μ s). In this way, the influence of the jitter in the measure is minimized.

In the device configuration tool of the GUI, perform a “Read” of the current device configuration, then tick the check-box “LS crystal measure” and perform a “Write” operation.

Now a power cycle is required to let the new device configuration be operative.

At this point, the 32.768 kHz waveform is visible on the oscilloscope screen.

Perform the measurement of the frequency: the difference between the target value ($f = 32.768$ kHz) and the measured one is the frequency offset Δf .

6.6 Expected results

If DUT frequency > 32.768 kHz → increases XTAL caps

If DUT frequency < 32.768 kHz → decreases XTAL caps

To find the frequency offset of the crystal oscillator in ppm, use the following formula:

$$ppm = \frac{\Delta f}{f} 10^6 \quad (1)$$

Δf = offset

$f = 32.768$ kHz

The total accuracy of the crystal oscillator is the sum of two parts: the accuracy, due to the offset, and the accuracy, due to temperature and aging, as reported in the crystal datasheet.

6.7 Note

The total accuracy of the low frequency oscillator must be given to the BLE stack during initialization, through the SleepClockAccuracy parameter (field of BLE_STACK_InitTypeDef).

6.8 Other

N/A.

7 Output power test

7.1 Test case specification identifier

OUTPUT_TESTS.

7.2 Test prerequisite

For this test the UFL or SMA connector is mandatory.

7.3 Test description

The aim of this test is verification of the Tx output power level and the step linearity.

7.4 Test setup

7.4.1 Hardware

A spectrum analyzer is required for this test.

7.4.2 Software

The ST BlueNRG GUI and DTM binary file loaded in the BlueNRG-LP/BlueNRG-LPS devices. Refer to [Section 1.1 DTM test applications](#).

7.5 Test procedure

Connect the BlueNRG-LP/BlueNRG-LPS boards to the spectrum analyzer through an RF cable. Set the spectrum analyzer to: Res BW = 100 kHz, SPAN = 500 kHz.

Power up the BlueNRG-LP/BlueNRG-LPS platforms.

Generate a carrier wave tone at Ch0 (frequency 2402 MHz) using the BlueNRG GUI, RF test window:

- Check the "high power" check-box to enable "high power mode" (SMPS level at 1.9 V)
- Select power level 31.
- Click on "Start Tone" button.

The same results can be achieved by using the ACI commands:

- ACI_HAL_SET_TX_POWER_LEVEL (En_High_Power = 0x01,PA_Level: 31)
- ACI_HAL_TONE_START (RF_Channel = 0x00, offset = 0x00).

7.6 Expected results

Spectrum analyzer measures a power value of around 8 dBm.

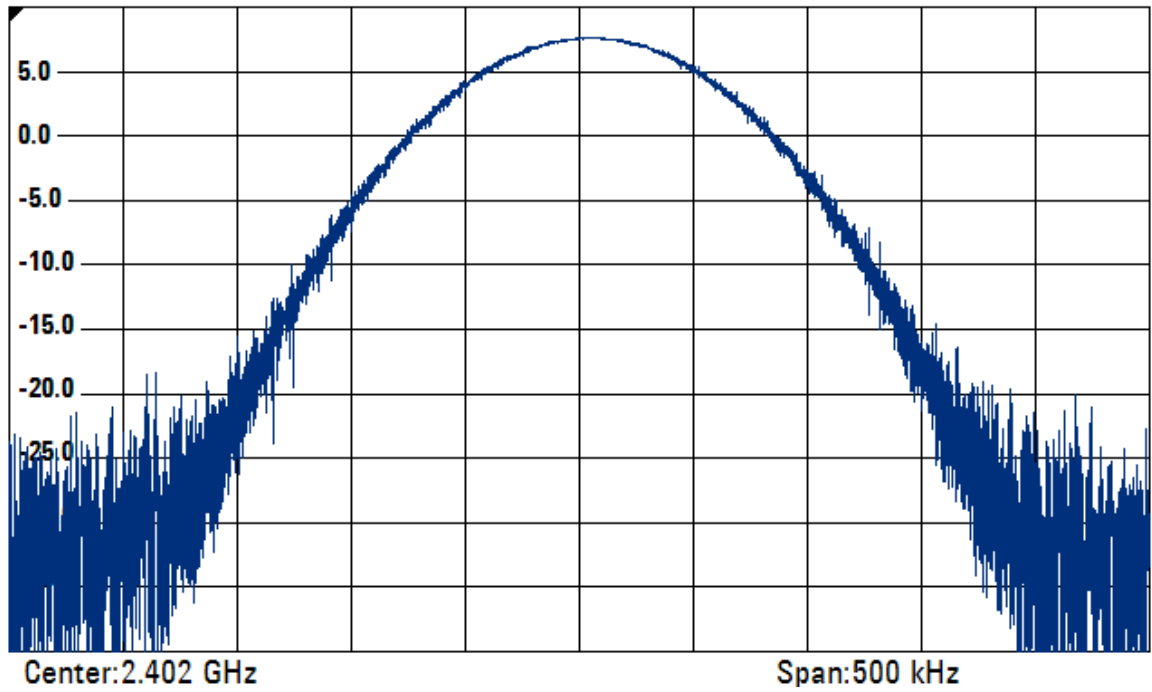
7.7 Note

The results are significantly influenced by the matching network performance. The user may need to tune it to obtain maximum performance.

7.8 Other

N/A

Figure 4. Output power measurement in high power mode with PA_level 31



8 Packet exchange test

8.1 Test case specification identifier

PACKET_TEST.

8.2 Test prerequisite

In order to perform these tests, two BlueNRG-LP/BlueNRG-LPS boards are used: one for the tester, the second one as the DUT. Tester must be a verified working board.

8.3 Test description

The aim of this test is to verify that the DUT board is able to send and receive packets correctly.

8.4 Test setup

8.4.1 Hardware

No instruments required.

8.4.2 Software

Load DTM firmware into the BlueNRG-LP/BlueNRG-LPS devices. Use the BlueNRG GUI to control the device. Refer to [Section 1.1 DTM test applications](#).

8.5 Test procedure

Power up the BlueNRG-LP/BlueNRG-LPS devices (tester and DUT boards) and ensure antennas are mounted. Follow these steps to start packet exchange test and verify that the DUT is able to receive:

In the GUI related to DUT (RX device)

- Go to RF test window, RECEIVER section
- Set Rx frequency
- Click on "Start Receiver" button, to start "Receiver Test".

In the GUI related to tester (TX device)

- Go to RF test window, TRANSMITTER section
- Set Tx power
- Set Tx frequency
- Set length of data to 0x25
- Set packet payload format
- Click on "Start Transmitter" button, to start "Transmitter Test".

In the GUI related to Tester (TX device)

- Click on "Stop Transmitter" button. The number of transmitted packets are displayed
- On #Packet Transmitted field.

In the GUI related to DUT (RX device)

- Click on "Stop Receiver" button. The number of received packets are displayed on the #Packet Received field
- In the PER section, insert the number of transmitted packets from Tx device in the packet transmitted field (read this value from the TRANSMITTER section in the GUI related to the Tx device)
- PER (packet error rate) value is shown in the packet error rate field.

The same results can be achieved by using the ACI commands:

- Start Rx on DUT: HCI_LE_ENHANCED_RECEIVER_TEST
- Make the Tx board send packets: HCI_LE_ENHANCED_TRANSMITTER_TEST, with the length of test data: 0x25
- Stop test on Tx board: HCI_LE_TEST_END
- Send this command in order to determine the number of packets sent by the Tx: ACI_HAL_LE_TX_TEST_PACKET_NUMBER
- Stop test on DUT: HCI_LE_TEST_END
- This returns Y as the number of received packets
- Exchange roles and repeat the same test to verify that DUT is able to transmit.

8.6 Expected results

In a "clean RF environment" (i.e. with no interference), the number of packets received over-the-air should be equal to the number of packets sent by the Tx board.

8.7 Note

Tester may be replaced by any other device with HCI interface.

8.8 Other

N/A.

9 Sensitivity test

9.1 Test case specification identifier

SENSITIVITY_TEST.

9.2 Test prerequisite

Two different hardware configurations can be adopted for this test:

1. A signal generator (Agilent E4438C, controlled through a GPIB interface) as Tx and the BlueNRG-1 board (DUT) connected as shown in [Figure 1. UFL connector](#).
2. ST BlueNRG-LP/BlueNRG-LPS demo kit as Tx device and BlueNRG-LP/BlueNRG-LPS board (DUT).

9.3 Test description

The aim of this test is to verify the sensitivity level of the DUT board.

9.4 Test setup

9.4.1 Hardware

Tx: Agilent E4438C signal generator or ST BlueNRG-LP/BlueNRG-LPS demo kit.

Rx: DUT application board to test (see [Figure 1. UFL connector](#)).

9.4.2 Software

ST BlueNRG GUI and DTM binary file related to the selected BLE stack modular configuration option loaded in the BlueNRG-LP/BlueNRG-LPS devices. Refer to [Section 1.1 DTM test applications](#).

9.5 Test procedure

Two procedures can be used.

9.5.1 Signal generator and DUT board

The sensitivity can be evaluated by performing the following steps:

1. Connect the instrument and DUT with an RF cable (with no significant loss)
2. Start Rx on DUT: on the RF test window click on "Start Receiver" button
3. Make the generator send X packets (well-formatted as described in "Direct Test Mode", vol. 6, part F, and "Host Controller Interface Functional Specification", vol. 2, part E, in point 3 [Section 13 References](#))
4. Stop test on DUT: on the RF test window click on stop receiver button

On packet received tab there is the number of received packets. PER is $1 - Y/X$.

If PER is below 0.308 (30.8%), go back to step 2 and decrease the power of the transmitter by one step. If PER goes above 0.308, then the level of power emitted by the equipment in the previous test is the sensitivity of the receiver. The algorithm can be more accurate by reducing the power level step when it is close to the sensitivity level.

The same results can be achieved by directly using the ACI commands:

1. Connect the instrument and DUT with an RF cable (with no significant loss)
2. Start Rx on DUT: HCI_LE_ENHANCED_RECEIVER_TEST
3. Make the generator send X packets (well-formatted as described in "Direct Test Mode", vol. 6, part F, and "Host Controller Interface Functional Specification", vol. 2, part E, in point 3 [Section 13 References](#))
4. Stop test on DUT: HCI_LE_TEST_END

This returns Y as the number of received packets. PER is 1-Y/X.

If PER is below 0.308 (30.8%), go back to step b and decrease the power of the transmitter by one step. If PER goes above 0.308, then the level of power emitted by the equipment in the previous test is the sensitivity of the receiver.

The algorithm can be more accurate by reducing the power level step when it is close to the sensitivity level.

9.5.2 ST demo kit and DUT board

In this case, the previous procedure changes in the following way:

1. Connect RF input/output of the two boards, DUT and ST BlueNRG-LP/BlueNRG-LPS , by using a variable attenuator
2. In the GUI related to DUT Rx device
 - Go to RF test window, RECEIVER section
 - Set Rx frequency
 - Click on "Start Receiver" button, to start "Receiver Test"
3. In the GUI related to Tx device
 - Go to RF test window, TRANSMITTER section
 - Set Tx power
 - Set Tx frequency
 - Set length of data to 0x25
 - Set packet payload format
 - Click on "Start Transmitter" button to start "Transmitter Test"
4. In the GUI related to Tx device
 - Click on "Stop Transmitter" button. The number of transmitted packets are displayed on #Packet Transmitted field.
5. In the GUI related to DUT Rx device
 - Click on "Stop Receiver" button. The number of received packets are displayed on #Packet Received field
6. In PER section, insert the number of transmitted packets from Tx device in the packet transmitted field (read this value from TRANSMITTER section in the GUI related to Tx device)
7. PER (packet error rate) value is shown in the packet error rate field

If PER is below 0.308 (30.8%), go back to step 2 and increase the value of attenuation. If PER goes above 0.308, then the level of power received by DUT in the previous test is the sensitivity of the receiver. It is very important to measure correctly or estimate the power received by DUT (for example: by using a tone instead of a modulated signal).

Moreover, in order to reduce the level of the signal received over-the-air by DUT, the ST BlueNRG-1 and BlueNRG-2 demo kit should use the minimum output power. Performing the measurements inside an anechoic chamber also gives more accurate results.

The same results can be achieved by using ACI commands:

1. Connect the RF input/output of the two boards, DUT and STM BlueNRG-1, by using a variable attenuator
2. Start Rx on DUT: HCI_LE_ENHANCED_RECEIVER_TEST
3. Make the board send packets: HCI_LE_ENHANCED_TRANSMITTER_TEST, with the length of test data: 0x25
4. Stop test on the board: HCI_LE_TEST_END
5. Send a further command to determine the number of packets sent by the board: ACI_HAL_LE_TX_TEST_PACKET_NUMBER
6. Stop test on DUT: HCI_LE_TEST_END

This returns Y as the number of received packets. PER is 1-Y/X.

If PER is below 0.308 (30.8%), go back to step 2 and increase the value of the attenuation. If PER goes above 0.308, then the level of power received by DUT in the previous test is the sensitivity of the receiver.

9.6 Expected results

The expected value should be a few dB from the value reported in the datasheet. If it is not so, the reason could be related to the matching network.

9.7 Note

Since the sensitivity test is very time-consuming, ST can provide a specific software for both hardware configurations in order to implement an automatic procedure.

9.8 Other

N/A.

10 Power consumption in advertising mode

10.1 Test case specification identifier

CURRENT_TEST.

10.2 Test prerequisite

In order to perform this test the platform must be provided with the test points in series with Vbat1, 2, 3 pins (see Table 1. Test points).

10.3 Test description

The aim of this test is to verify that BlueNRG-LP/BlueNRG-LPS current consumption profile during the advertising is aligned with the simulated value (for simulated values use the BlueNRG current consumption estimation tool (STSW-BNRG001) available on www.st.com).

10.4 Test setup

10.4.1 Hardware

Agilent N6705B power analyzer or an oscilloscope.

10.4.2 Software

This test uses an application, which puts the device in advertising mode (i.e. power consumption example available on the BlueNRG-LP/BlueNRG-LPS DK development kit/STSW-BNRGLP-DK, on Firmware/ BLE_Examples folder).

10.5 Test procedure

The power analyzer has to be connected in series to Vbat pins in BlueNRG-LP/BlueNRG-LPS. If it is not available, a 10 Ohm resistor has to be used to sense the current, connecting two probes to it.

Power up the BlueNRG-LP/BlueNRG-LPS platform and load a firmware so that the device is in advertising mode. Capture the current waveform.

10.6 Expected results

The average current should be measured using the power analyzer tool (see [Figure 5. Typical current profile during an advertising event](#)).

The measured values are significantly influenced by the device configuration parameters, such as: the HS_Startup_Time and the 32 kHz crystal (external or internal ring oscillator).

Figure 5. Typical current profile during an advertising event



10.7 **Note**
N/A.

10.8 **Other**
N/A.

11 RF tests for certification

Tests described in this application note should be used to check the basic functionality of the BlueNRG-LP/BlueNRG-LPS devices on prototype boards.

Before Bluetooth trademark can be used on the BlueNRG-LP/BlueNRG-LPS devices, the company must complete the Bluetooth compliance program; that means the board must be qualified and listed.

Since the BlueNRG-LP/BlueNRG-LPS are an already qualified product, a board using the BlueNRG-LP/BlueNRG-LPS devices does not have to re-run all Bluetooth tests. However, when the BlueNRG-LP/BlueNRG-LPS support is used in a new RF design, the RF-PHY layer must be still tested. To know which tests are to be performed, refer to the current test case reference list (TCRL) and related RF-PHY test specifications on the official Bluetooth website (<http://bluetooth.com/>).

Moreover, depending on the country of use, an RF product must be compliant with one or more standards before it can be sold. In particular, Bluetooth low energy products, which operate in the unlicensed ISM band at 2.4 GHz, must be compliant to:

- FCC part 15.205, 15.209, 15.247 in North America
- ETSI EN 300 328 in Europe
- ARIB STD-T66 in Japan.

Bluetooth LE tests can be manually performed, but some instruments exist to simplify and automate the testing process.

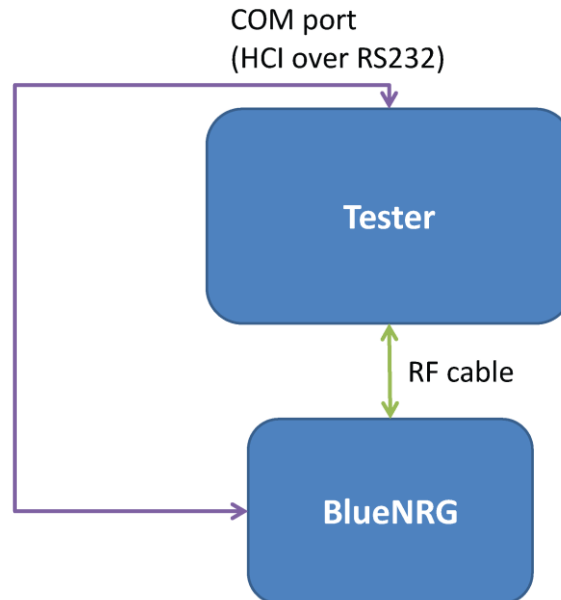
Usually these instruments operate in two modes:

- Signaling mode
- Non-signaling mode.

11.1 Signaling mode

In this mode, the instrument can autonomously perform the tests. DUT (device under test) must be connected to the instrument with an RF cable. Moreover, DUT has to be connected to one instrument port in order to be controlled by the instrument itself (to start/stop test and receive feedback from DUT). The BlueNRG-LP/BlueNRG-LPS support the direct test mode over HCI, which allows testing low energy PHY layer (see Bluetooth specifications, vol. 6, part F: direct test mode).

Figure 6. Signaling mode RF tests

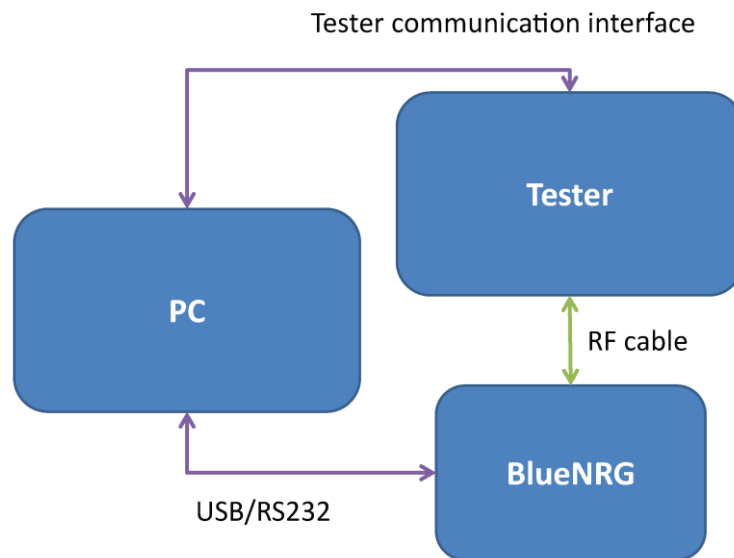


On the test equipment, the serial port for communication with DUT is typically an RS232 interface. The BlueNRG-LP/BlueNRG-LPS come with a UART interface that can be easily made compatible to an RS-232 interface. A level translator is usually needed to adapt the different voltage requirements on the two interfaces.

11.2 Non-signaling mode

In non-signaling mode a third entity (e.g. a PC) controls both DUT and Test instrument at the same time. Typically, the instrument can be controlled by using proprietary commands. The BlueNRG-LP/BlueNRG-LPS can use either UART or SPI as the communication interface. The device can be connected to the PC through a serial-to-USB converter.

Figure 7. Non-signaling mode RF tests



12 RF tests for board manufacturing

Once the final board has been designed and sent to production, the manufacturer may want to run some basic tests to be confident that the device works correctly. The minimal set of suggested tests is:

- Output power (see [Section 7 Output power test](#)) and crystal frequency centering test (see [Section 5 HSOSC centering test](#))
- Packet exchange test (see [Section 8 Packet exchange test](#)).

Some of these tests can also be performed by dedicated instruments, as described in [Section 11.1 Signaling mode](#). In this case, the set of tests to be performed is:

- Output power
- Carrier frequency offset and drift
- Receiver sensitivity.

13 References

1. BlueNRG-LP datasheet (DS13282)
2. BlueNRG-LPS datasheet (DS13819)
3. BlueNRG GUI SW package (STSW-BNRGUI) user manual (UM2058)
4. RF-Flasher utility (STSW-BNRGFLASHER) user manual (UM2406)

Revision history

Date	Version	Changes
27-Jul-2020	1	Initial release.
12-May-2021	2	Updated Section 6 LSOSC centering test.
06-Apr-2022	3	Updated Section Introduction , Section 1.1 DTM test applications, Section 3 Device configuration and Section 13 References. Updated Figure 1 . UFL connector. Added the BlueNRG-LPS references throughout the document.

Contents

1	Application PCB test points	2
1.1	DTM test applications	2
2	Power supply test	3
2.1	Test case specification identifier	3
2.2	Test prerequisite	3
2.3	Test description	3
2.4	Test setup	3
2.4.1	Hardware	3
2.4.2	Software	3
2.5	Test procedure	3
2.6	Expected results	3
2.7	Note	4
2.8	Other	4
3	Device configuration	5
4	HS_Startup_Time	6
4.1	Test case specification identifier	6
4.2	Test prerequisite	6
4.3	Test description	6
4.4	Test setup	6
4.4.1	Hardware	6
4.4.2	Software	6
4.5	Test procedure	6
4.6	Expected results	6
4.7	Note	7
4.8	Other	7
5	HSOSC centering test	8
5.1	Test case specification identifier	8
5.2	Test prerequisite	8
5.3	Test description	8

5.4	Test setup	8
5.4.1	Hardware	8
5.4.2	Software	8
5.5	Test procedure	8
5.6	Expected results	9
5.7	Note	9
5.8	Other	9
6	LSOSC centering test	10
6.1	Test case specification identifier	10
6.2	Test prerequisite	10
6.3	Test description	10
6.4	Test setup	10
6.4.1	Hardware	10
6.4.2	Software	10
6.5	Test procedure	10
6.6	Expected results	10
6.7	Note	11
6.8	Other	11
7	Output power test	12
7.1	Test case specification identifier	12
7.2	Test prerequisite	12
7.3	Test description	12
7.4	Test setup	12
7.4.1	Hardware	12
7.4.2	Software	12
7.5	Test procedure	12
7.6	Expected results	12
7.7	Note	12
7.8	Other	12
8	Packet exchange test	14
8.1	Test case specification identifier	14

8.2	Test prerequisite	14
8.3	Test description	14
8.4	Test setup	14
8.4.1	Hardware	14
8.4.2	Software	14
8.5	Test procedure	14
8.6	Expected results	15
8.7	Note	15
8.8	Other	15
9	Sensitivity test.....	16
9.1	Test case specification identifier	16
9.2	Test prerequisite	16
9.3	Test description	16
9.4	Test setup	16
9.4.1	Hardware	16
9.4.2	Software	16
9.5	Test procedure	16
9.5.1	Signal generator and DUT board	16
9.5.2	ST demo kit and DUT board	17
9.6	Expected results	18
9.7	Note	18
9.8	Other	18
10	Power consumption in advertising mode.....	19
10.1	Test case specification identifier	19
10.2	Test prerequisite	19
10.3	Test description	19
10.4	Test setup	19
10.4.1	Hardware	19
10.4.2	Software	19
10.5	Test procedure	19
10.6	Expected results	19

10.7	Note	20
10.8	Other	20
11	RF tests for certification	21
11.1	Signaling mode	21
11.2	Non-signaling mode	22
12	RF tests for board manufacturing	24
13	References	25
	Revision history	26

List of tables

Table 1.	Test points	2
Table 2.	Supply test results	3

List of figures

Figure 1.	UFL connector	2
Figure 2.	BlueNRG GUI device configuration tool	5
Figure 3.	Frequency tone at Ch0 for the XTAL center test	9
Figure 4.	Output power measurement in high power mode with PA_level 31	13
Figure 5.	Typical current profile during an advertising event	20
Figure 6.	Signaling mode RF tests	22
Figure 7.	Non-signaling mode RF tests	23

IMPORTANT NOTICE – READ CAREFULLY

STMicroelectronics NV and its subsidiaries (“ST”) reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST’s terms and conditions of sale in place at the time of order acknowledgment.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of purchasers’ products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. For additional information about ST trademarks, refer to www.st.com/trademarks. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2022 STMicroelectronics – All rights reserved